


<b>Search Notes</b>  	<b>Application/Control No.</b>  10701167	<b>Applicant(s)/Patent Under Reexamination</b>  CHAULK ET AL.
	<b>Examiner</b>  CHAU NGUYEN	<b>Art Unit</b>  2176

SEARCHED			
Class	Subclass	Date	Examiner
715	200	02/14/2008	cn
715	212	02/14/2008	cn
715	213	02/14/2008	cn
715	214	02/14/2008	cn
715	220	02/14/2008	cn
715	229	02/14/2008	cn
715	238	02/14/2008	cn
715	242	02/14/2008	cn
715	252	02/14/2008	cn
715	255	02/14/2008	cn
707	1	02/14/2008	cn
707	7	02/14/2008	cn
707	200	02/14/2008	cn

SEARCH NOTES		
Search Notes	Date	Examiner
Updated Search on East Reports	02/13/2008	cn
	02/14/2008	cn
Interference Search on PGPUB	02/14/2008	cn
NPL Search on IEEE Database	02/14/2008	cn
Inventor Search for Double Patenting	02/14/2008	cn

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
715	200	02/14/2008	cn
715	212	02/14/2008	cn
715	213	02/14/2008	cn
715	214	02/14/2008	cn
715	220	02/14/2008	cn
715	229	02/14/2008	cn
715	238	02/14/2008	cn
715	242	02/14/2008	cn
715	252	02/14/2008	cn
715	255	02/14/2008	cn
707	1	02/14/2008	cn
707	7	02/14/2008	cn

## INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
707	200	02/14/2008	